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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/809,974	CHEN ET AL.	
Examiner	Art Unit	

2826

Tuan Quach

SEARCHED					
Class	Subclass	Date	Examiner		
257	295, 310, 368, 410, 411	6/25/2006	ΤQ		
(update	search)				

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST (USPAT; USPGPUG; EPO; JPO; DERWENT; IBMTDB) - see search history printout	6/25/2006	TQ	
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